

MIPS_Process

MIPS_Verify, MIPS_SPC Real Time, MIPS_SPC WEB (History)

The **MIPS_Process Unit** is a comprehensive solution for defect verification, defect management and repair as well as statistical process control in production. It is capable of in-line or off-line verification and is fully configurable for the best process integration. The **MIPS_Process Unit** is composed of the modules **MIPS_Verify**, **MIPS_SPC Real Time** and **MIPS_SPC Web (History)**:

MIPS_Verify can be linked to automatic AXI/AOI inspection systems for closed loop verification & repair.

The software offers optimum operator support for verification of the defect images. Different kind of images of the same defect (e.g. transmission, SFT, off-axis, AOI) can be displayed at the same time to facilitate evaluation. The new Tune plugin allows proceeding algorithms on defect images in MIPS_Verify. In consequence the parameters for the joint type of your choice are then presented in colours, including e.g. a percentage analysis for voids.

The **MIPS_SPC Real Time** module provides real time process control for immediate production line feedback.

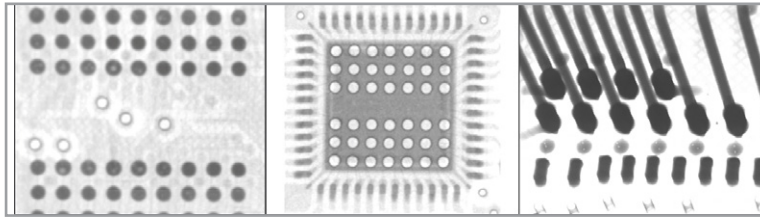
MIPS_SPC Web is a web-based tool statistically processing inspection data provided by MIPS_Verify allowing yield control and optimizing of production process and inspection lists.

Features and Benefits

MIPS_Verify

MIPS_SPC Real Time

- Modular Verification Software with interfaces to all other MIPS Software Units
- Defect Verification, Defect Management and Defect Archiving
- Parallel display of transmission, off-axis, slice image, SFT™ or optical image
- Easy to use, flexible GUI
- Integrated User Management
- Multilanguage support (per user)
- X-Ray defect image with defect marking
- Defect message library (customer specified)
- Defect status classification
- Standard file formats and proprietary formats of supported systems
- Input and Output Converters for a variety of AXI and AOI Systems.
- Statistical Process Control with yield verification
- The traceability of the test devices is guaranteed throughout the whole inspection process
- Context sensitive link to Mips module defect image library
- Statistical Process Control with yield verification



For more information, speak with your **MatriX** representative.

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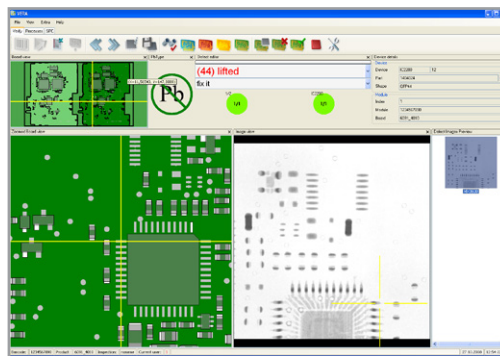
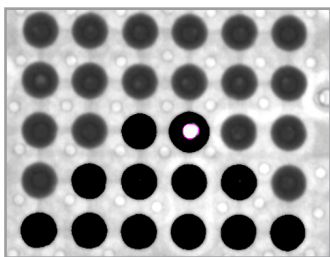
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Verification

- Hands off defect identification and repair verification
- Display of X-ray image with defect location marked
- Tune Plugin for coloured algorithm parameter presentation and display of an extract of measurement values (e.g. void percentage) of a selected joint type



- Can be configured for verification and/or repair
- Reporting output is in standard ASCII format
- Fully configurable for best process integration

Statistical Process Control (Real time)

- Real time attribute measurement collection and display
- Board layout quickly identifies defect distribution
- Statistics reported at the device, component and pin level
- SPC data can classify the source of defect by process step
- Report filters identify process drifts and trend analysis data configurable for best process integration
- Yield Verification
- Fully configurable for best process integration

